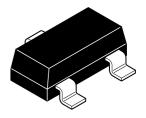


ZXMN2B14FH 20V SOT23 N-channel enhancement mode MOSFET with low gate drive capability

Summary

V _{(BR)DSS}	$R_{DS(on)}$ (Ω)	I _D (A)
	0.055 @ V _{GS} = 4.5V	4.3
20	0.075 @ V _{GS} = 2.5V	3.7
	0.100 @ V _{GS} = 1.8V	3.2

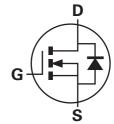


Description

This new generation of trench MOSFETs from Zetex features low onresistance achievable with low gate drive.

Features

- · Low on-resistance
- · Fast switching speed
- · Low gate drive capability
- SOT23 package

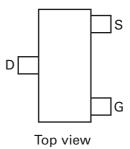


Applications

- DC-DC converters
- · Power management functions
- · Disconnect switches
- Motor control

Ordering information

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2B14FHTA	7	8	3,000



Device marking

2B4

Absolute maximum ratings

Parameter	Symbol	Limit	Unit	
Drain-source voltage	V_{DSS}	20	V	
Gate-source voltage		V_{GS}	± 8	V
Continuous drain current	@ V_{GS} = 4.5V; T_{amb} =25°C (b)	I _D	4.3	Α
	@ V_{GS} = 4.5V; T_{amb} =70°C (b)		3.5	
	@ V_{GS} = 4.5V; T_{amb} =25°C (a)		3.5	
Pulsed drain current (c)	I _{DM}	21	Α	
Continuous source current	I _S	2.4	Α	
Pulsed source current (bod	I _{SM}	21	Α	
Power dissipation at T _{amb} =	P_{D}	1	W	
Linear derating factor		8	mW/°C	
Power dissipation at T _{amb} =	P_{D}	1.5	W	
Linear derating factor		12	mW/°C	
Operating and storage tem	T _j , T _{stg}	-55 to +150	°C	

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient	$R_{\Theta JA}$	125	°C/W
Junction to ambient	$R_{\Theta JA}$	82	°C/W

NOTES:

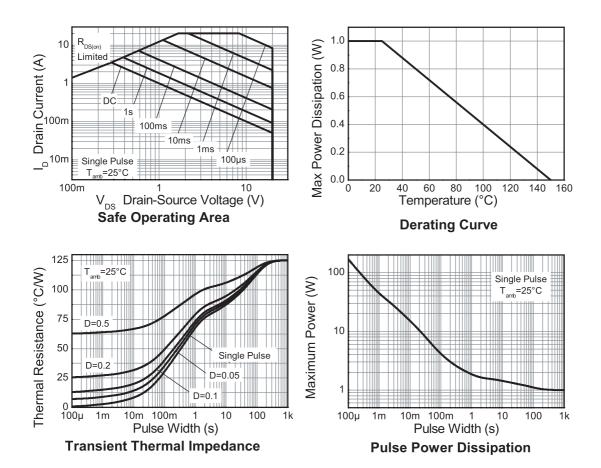
⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

⁽b) For a device surface mounted on FR4 PCB measured at t \leq 5 sec.

⁽c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width $300\mu s$ - pulse width limited by maximum junction temperature.

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Thermal characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static	1		l			
Drain-source breakdown voltage	V _{(BR)DSS}	20			V	I _D = 250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			1	μΑ	V _{DS} = 20V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±8V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	0.4		1.0	V	I _D = 250μA, V _{DS} =V _{GS}
Static drain-source on-state	R _{DS(on)}			0.055	Ω	V _{GS} = 4.5V, I _D = 3.5A
resistance (*)				0.075	Ω	$V_{GS} = 2.5V, I_{D} = 3A$
				0.100	Ω	V_{GS} = 1.8V, I_{D} = 2.6A
Forward transconductance(*) (‡)	9 _{fs}		11		S	V _{DS} = 10V, I _D = 3.5A
Dynamic ^(‡)						
Input capacitance	C _{iss}		872		pF	V _{DS} = 10V, V _{GS} =0V
Output capacitance	C _{oss}		145		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		90		pF	
Switching (†) (‡)						
Turn-on-delay time	t _{d(on)}		3.7		ns	V _{DD} = 10V, V _{GS} = 4.5V
Rise time	t _r		5.2		ns	I _D = 1A
Turn-off delay time	t _{d(off)}		30		ns	$R_{G} \approx 6.0\Omega$
Fall time	t _f		5.5		ns	
Total gate charge	Qg		11		nC	V _{DS} = 10V, V _{GS} = 4.5V
Gate-source charge	Q_{gs}		1.4		nC	I _D = 4.0A
Gate drain charge	Q _{gd}		2.1		nC	
Source-drain diode						
Diode forward voltage ^(*)	V_{SD}		0.69	0.95	V	T _j =25°C, I _S = 1.45A, V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		9.4		ns	T _j =25°C, I _F = 2.4A,
Reverse recovery charge ^(‡)	Q _{rr}		2.8		nC	di/dt=100A/μs

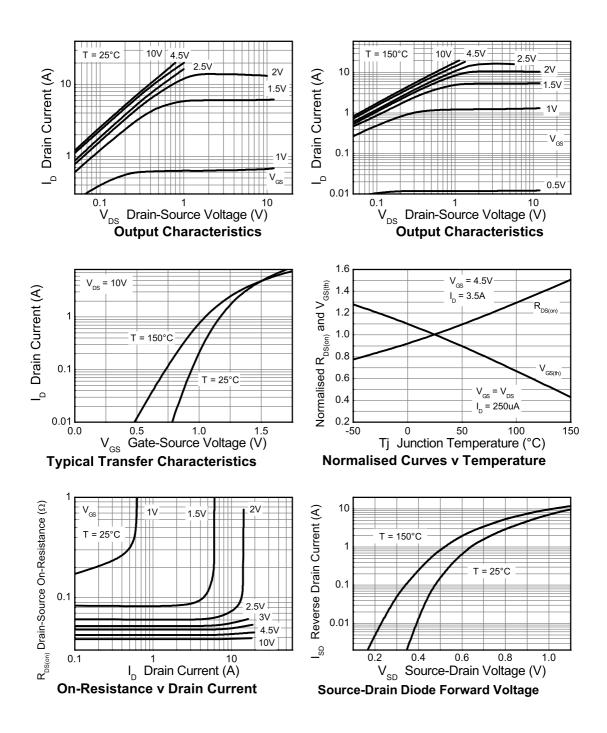
NOTES:

^(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu s;$ duty cycle ${\leq}2\%.$

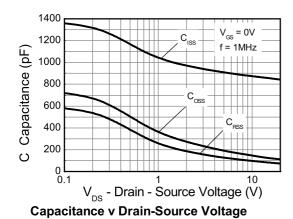
^(†) Switching characteristics are independent of operating junction temperature.

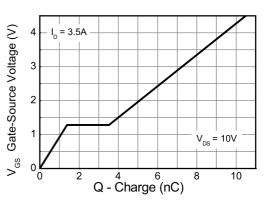
^(‡) For design aid only, not subject to production testing.

Typical characteristics

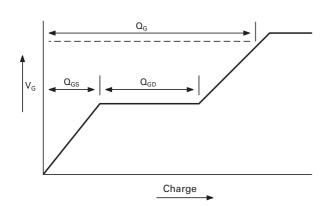


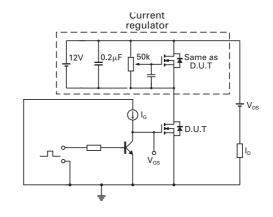
Typical characteristics





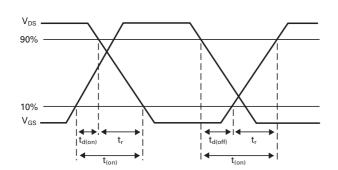
Gate-Source Voltage v Gate Charge

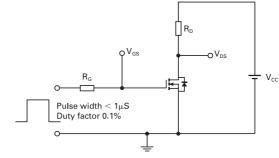




Basic gate charge waveform

Gate charge test circuit



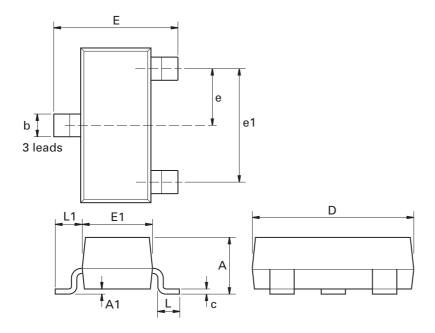


Switching time waveforms

Switching time test circuit

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Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
Α	-	1.12	-	0.044	e1	1.90 NOM		0.075 NOM	
A1	0.01	0.10	0.0004	0.004	Е	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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